

10-TAP, TTL-INTERFACED FIXED DELAY LINE (SERIES DDU7C)

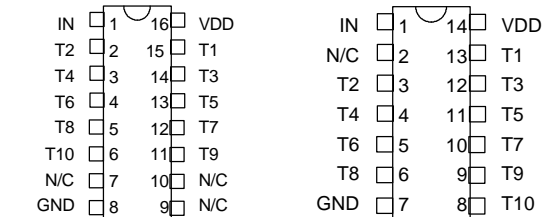
**data
delay
devices, inc.**



FEATURES

- Ten equally spaced outputs
- Fits standard 16-pin DIP socket
- Low profile
- Auto-insertable
- Input & outputs fully CMOS interfaced & buffered
- 10 T²L fan-out capability

PACKAGES



DDU7C-xx DIP
DDU7C-xxA3 Gull-Wing
DDU7C-xxB3 J-Lead
DDU7F-xxMC3 Military SMD

Military DIP
DDU7C-xxM

FUNCTIONAL DESCRIPTION

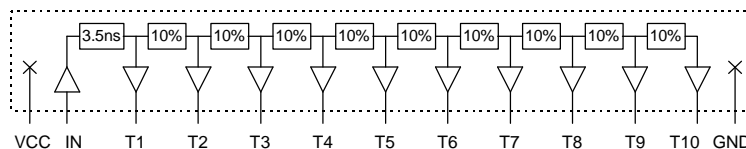
The DDU7C-series device is a 10-tap digitally buffered delay line. The signal input (IN) is reproduced at the outputs (T1-T10), shifted in time by an amount determined by the device dash number. The nominal tap-to-tap delay increment is given by 1/10 of the dash number. For dash numbers less than 50, the total delay of the line is measured from T1 to T10, with the nominal value given by 9 times the increment. The inherent delay from IN to T1 is nominally 8.0ns. For dash numbers greater than or equal to 50, the total delay of the line is measured from IN to T10, with the nominal value given by the dash number.

PIN DESCRIPTIONS

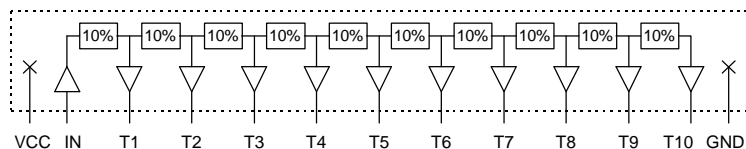
IN Signal Input
T1-T10 Tap Outputs
VDD +5 Volts
GND Ground

SERIES SPECIFICATIONS

- **Minimum input pulse width:** 20% of total delay
- **Output rise time:** 8ns typical
- **Supply voltage:** 5VDC \pm 5%
- **Supply current:** $I_{CCL} = 40\mu\text{a}$ typical
 $I_{CCH} = 10\text{ma}$ typical
- **Operating temperature:** 0° to 70° C
- **Temp. coefficient of total delay:** 300 PPM/°C



Functional diagram for dash numbers < 50



Functional diagram for dash numbers \geq 50

DASH NUMBER SPEC.'S

Part Number	Total Delay (ns)	Delay Per Tap (ns)
DDU7C-25	22.5 \pm 2.0 *	2.5 \pm 1.0
DDU7C-100	100 \pm 5.0	10.0 \pm 2.0
DDU7C-150	150 \pm 7.5	15.0 \pm 2.0
DDU7C-200	200 \pm 10.0	20.0 \pm 2.0
DDU7C-250	250 \pm 12.5	25.0 \pm 2.0
DDU7C-300	300 \pm 15.0	30.0 \pm 3.0
DDU7C-400	400 \pm 20.0	40.0 \pm 4.0
DDU7C-500	500 \pm 25.0	50.0 \pm 5.0

* Total delay is referenced to first tap
Input to first tap = 8.0ns \pm 2ns

NOTE: Any dash number between 25 and 500 not shown is also available.

APPLICATION NOTES

HIGH FREQUENCY RESPONSE

The DDU7C tolerances are guaranteed for input pulse widths and periods greater than those specified in the test conditions. Although the device will function properly for pulse widths as small as 20% of the total delay and periods as small as 40% of the total delay (for a symmetric input), the delays may deviate from their values at low frequency. However, for a given input condition, the deviation will be repeatable from pulse to pulse. Contact technical support at Data

Delay Devices if your application requires device testing at a specific input condition.

POWER SUPPLY BYPASSING

The DDU7C relies on a stable power supply to produce repeatable delays within the stated tolerances. A 0.1 μ f capacitor from VDD to GND, located as close as possible to the VDD pin, is recommended. A wide VDD trace and a clean ground plane should be used.

DEVICE SPECIFICATIONS

TABLE 1: ABSOLUTE MAXIMUM RATINGS

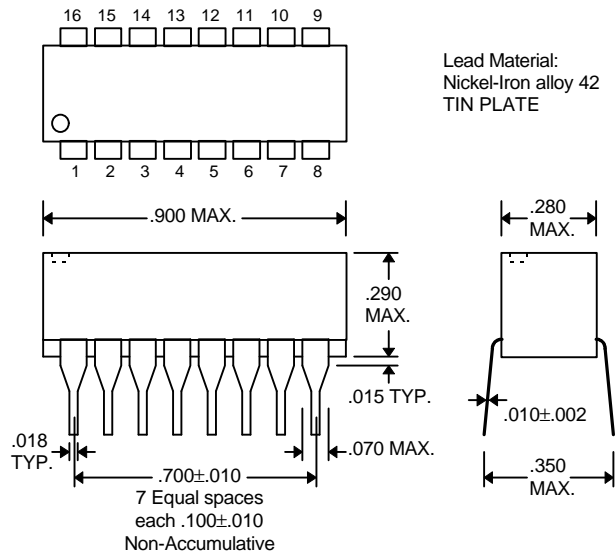
PARAMETER	SYMBOL	MIN	MAX	UNITS	NOTES
DC Supply Voltage	V_{CC}	-0.3	7.0	V	
Input Pin Voltage	V_{IN}	-0.3	$V_{DD}+0.3$	V	
Storage Temperature	T_{STRG}	-55	150	C	
Lead Temperature	T_{LEAD}		300	C	10 sec

TABLE 2: DC ELECTRICAL CHARACTERISTICS

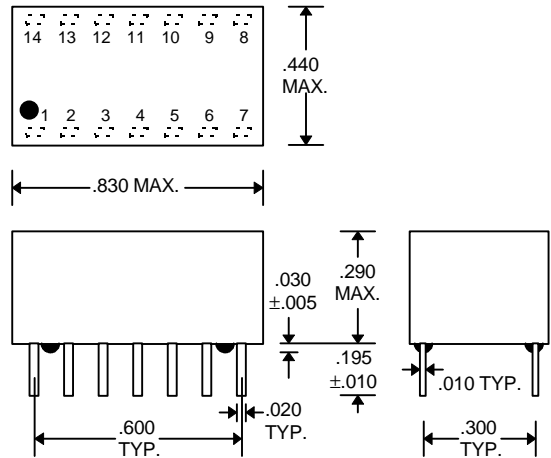
(0C to 70C, 4.75V to 5.25V)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
High Level Output Voltage	V_{OH}	3.98	4.4		V	$V_{DD} = 5.0$, $I_{OH} = MAX$ $V_{IH} = MIN$, $V_{IL} = MAX$
Low Level Output Voltage	V_{OL}		0.15	0.26	V	$V_{DD} = 5.0$, $I_{OL} = MAX$ $V_{IH} = MIN$, $V_{IL} = MAX$
High Level Output Current	I_{OH}			-4.0	mA	
Low Level Output Current	I_{OL}			4.0	mA	
High Level Input Voltage	V_{IH}	3.15			V	
Low Level Input Voltage	V_{IL}			1.35	V	
Input Current	I_{IH}			0.10	μ A	$V_{DD} = 5.0$

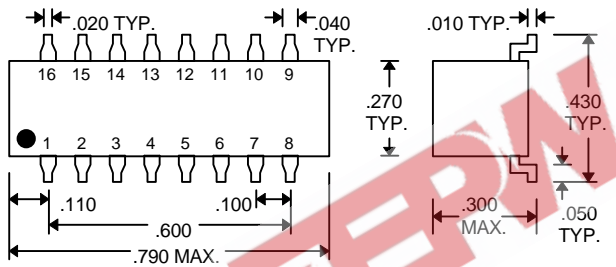
PACKAGE DIMENSIONS



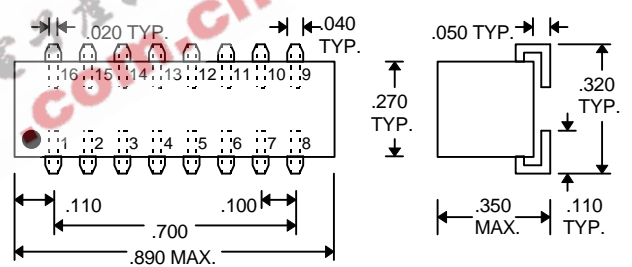
DDU7C-xx (Commercial DIP)



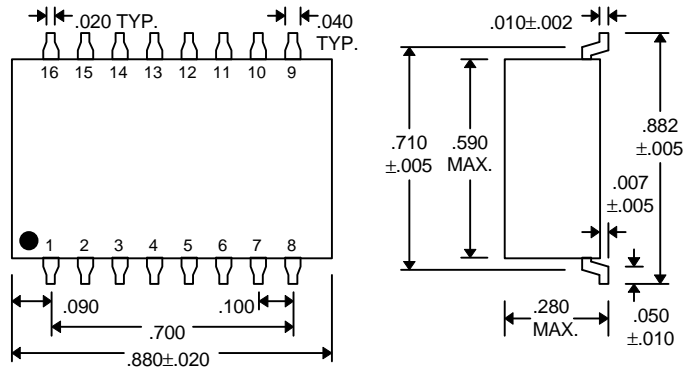
DDU7C-xxM (Military DIP)



DDU7C-xxA3 (Commercial Gull-Wing)



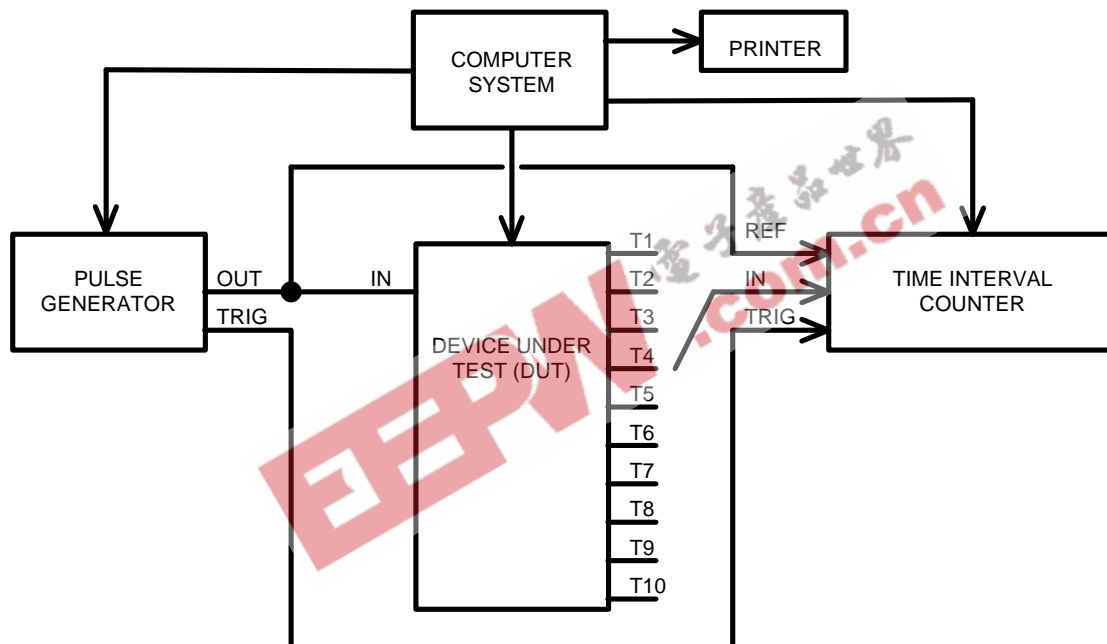
DDU7C-xxB3 (Commercial J-Lead)



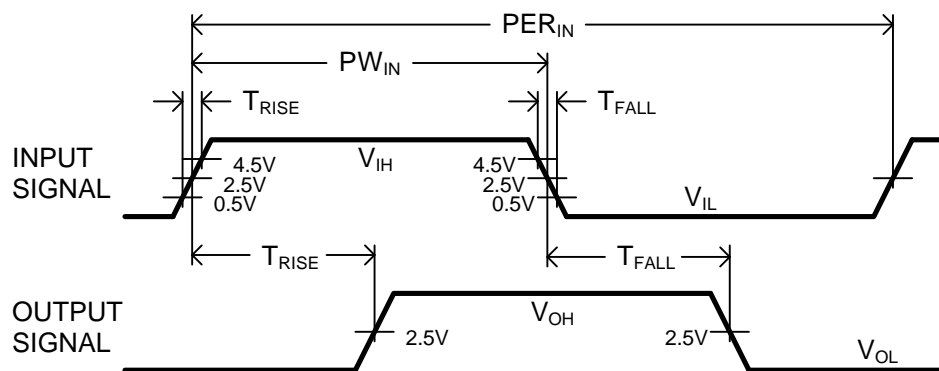
DDU7C-xxMC3 (Military Gull-Wing)

DELAY LINE AUTOMATED TESTING

TEST CONDITIONS

INPUT:**Ambient Temperature:** $25^{\circ}\text{C} \pm 3^{\circ}\text{C}$ **Supply Voltage (Vcc):** $5.0\text{V} \pm 0.1\text{V}$ **Input Pulse:** High = $5.0\text{V} \pm 0.1\text{V}$
Low = $0.0\text{V} \pm 0.1\text{V}$ **Source Impedance:** 50Ω Max.**Rise/Fall Time:** 5.0 ns Max. (measured
between 0.5V and 4.5V)**Pulse Width:** $\text{PW}_{\text{IN}} = 1.5 \times \text{Total Delay}$ **Period:** $\text{PER}_{\text{IN}} = 10 \times \text{Total Delay}$ **OUTPUT:****Load:** 1 FAST-TTL Gate**C_{load}:** 5pf \pm 10%**Threshold:** 2.5V (Rising & Falling)**NOTE:** The above conditions are for test only and do not in any way restrict the operation of the device.

Test Setup



Timing Diagram For Testing